International TOR Rectifier

IRL3705N

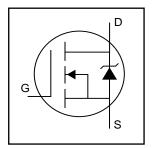
HEXFET® Power MOSFET

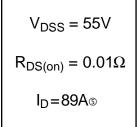
- Logic-Level Gate Drive
- Advanced Process Technology
- Dynamic dv/dt Rating
- 175°C Operating Temperature
- Fast Switching
- Fully Avalanche Rated

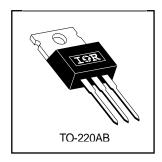
Description

Fifth Generation HEXFETs from International Rectifier utilize advanced processing techniques to achieve extremely low on-resistance per silicon area. This benefit, combined with the fast switching speed and ruggedized device design that HEXFET Power MOSFETs are well known for, provides the designer with an extremely efficient and reliable device for use in a wide variety of applications.

The TO-220 package is universally preferred for all commercial-industrial applications at power dissipation levels to approximately 50 watts. The low thermal resistance and low package cost of the TO-220 contribute to its wide acceptance throughout the industry.







Absolute Maximum Ratings

	Parameter	Max.	Units
I _D @ T _C = 25°C	Continuous Drain Current, V _{GS} @ 10V	89⑤	
I _D @ T _C = 100°C	Continuous Drain Current, V _{GS} @ 10V	63	A
I _{DM}	Pulsed Drain Current ①	310	
P _D @T _C = 25°C	Power Dissipation	170	W
	Linear Derating Factor	1.1	W/°C
V_{GS}	Gate-to-Source Voltage	± 16	V
E _{AS}	Single Pulse Avalanche Energy②	340	mJ
I _{AR}	Avalanche Current①	46	A
E _{AR}	Repetitive Avalanche Energy①	17	mJ
dv/dt	Peak Diode Recovery dv/dt ③	5.0	V/ns
T _J	Operating Junction and	-55 to + 175	
T _{STG}	Storage Temperature Range		°C
	Soldering Temperature, for 10 seconds	300 (1.6mm from case)	
	Mounting torque, 6-32 or M3 srew	10 lbf•in (1.1N•m)	

Thermal Resistance

	Parameter	Тур.	Max.	Units
$R_{\theta JC}$	Junction-to-Case		0.90	
$R_{\theta CS}$	Case-to-Sink, Flat, Greased Surface	0.50		°C/W
$R_{\theta JA}$	Junction-to-Ambient		62	

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Electrical Characteristics @ T_J = 25°C (unless otherwise specified)

	Parameter	Min.		Max.		Conditions
V _{(BR)DSS}	Drain-to-Source Breakdown Voltage	55			V	$V_{GS} = 0V, I_D = 250\mu A$
$\Delta V_{(BR)DSS}/\Delta T_J$	Breakdown Voltage Temp. Coefficient		0.056		V/°C	Reference to 25°C, I _D = 1mA
				0.010		V _{GS} = 10V, I _D = 46A ④
R _{DS(on)}	Static Drain-to-Source On-Resistance			0.012	Ω	V _{GS} = 5.0V, I _D = 46A ④
				0.018		V _{GS} = 4.0V, I _D = 39A ④
V _{GS(th)}	Gate Threshold Voltage	1.0		2.0	V	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$
9 _{fs}	Forward Transconductance	50			S	$V_{DS} = 25V, I_D = 46A$
	Dunin to Course Lealings Comment			25		$V_{DS} = 55V, V_{GS} = 0V$
I _{DSS}	Drain-to-Source Leakage Current			250	μA	V _{DS} = 44V, V _{GS} = 0V, T _J = 150°C
1	Gate-to-Source Forward Leakage			100	nA	V _{GS} = 16V
I _{GSS}	Gate-to-Source Reverse Leakage			-100	114	V _{GS} = -16V
Qg	Total Gate Charge			98		I _D = 46A
Q _{gs}	Gate-to-Source Charge			19	nC	$V_{DS} = 44V$
Q _{gd}	Gate-to-Drain ("Miller") Charge			49		V_{GS} = 5.0V, See Fig. 6 and 13 \oplus
t _{d(on)}	Turn-On Delay Time		12			$V_{DD} = 28V$
t _r	Rise Time		140		ns	$I_D = 46A$
t _{d(off)}	Turn-Off Delay Time		37		115	$R_G = 1.8\Omega, V_{GS} = 5.0V$
t _f	Fall Time		78			$R_D = 0.59\Omega$, See Fig. 10 $\textcircled{4}$
L _D	Internal Drain Inductance		4.5		— nH	Between lead,
						6mm (0.25in.)
L _S	Internal Source Inductance		7.5	_		from package
						and center of die contact
C _{iss}	Input Capacitance		3600			$V_{GS} = 0V$
C _{oss}	Output Capacitance		870		pF	$V_{DS} = 25V$
Crss	Reverse Transfer Capacitance		320		1	f = 1.0MHz, See Fig. 5

Source-Drain Ratings and Characteristics

	Parameter	Min.	Тур.	Max.	Units	Conditions
Is	Continuous Source Current	8	89 [©]	9\$ A	MOSFET symbol	
	(Body Diode)				showing the	
I _{SM}	Pulsed Source Current			310	^	integral reverse
	(Body Diode) ①				0	p-n junction diode.
V _{SD}	Diode Forward Voltage			1.3	V	T _J = 25°C, I _S = 46A, V _{GS} = 0V ④
t _{rr}	Reverse Recovery Time		94	140	ns	$T_J = 25$ °C, $I_F = 46A$
Q _{rr}	Reverse RecoveryCharge		290	440	nC	di/dt = 100A/µs ④
t _{on}	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by L _S +L _D)				

Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11)
- \mathbb{Q} V_{DD} = 25V, starting T_J = 25°C, L = 320μH R_G = 25Ω, I_{AS} = 46A. (See Figure 12)
- $\label{eq:loss} \begin{array}{l} \text{ $I_{SD} \leq 46A$, di/dt} \leq 250A/\mu s$, $V_{DD} \leq V_{(BR)DSS}$,} \\ T_J \leq 175^{\circ}C \end{array}$
- ⓐ Pulse width ≤ 300 μ s; duty cycle ≤ 2%.
- S Calculated continuous current based on maximum allowable junction temperature; for recommended current-handling of the package refer to Design Tip # 93-4

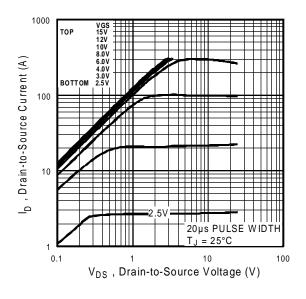


Fig 1. Typical Output Characteristics

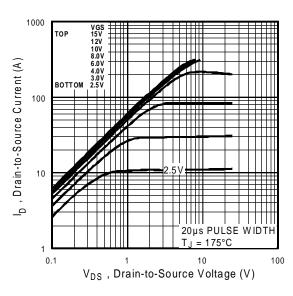


Fig 2. Typical Output Characteristics

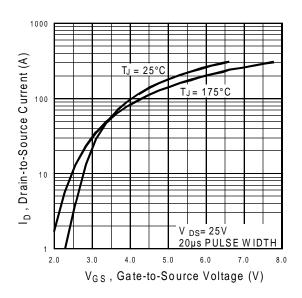


Fig 3. Typical Transfer Characteristics

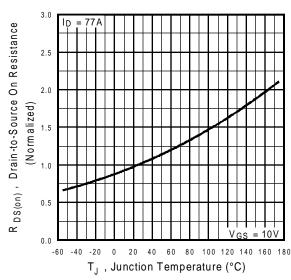


Fig 4. Normalized On-Resistance Vs. Temperature

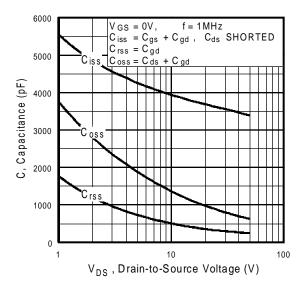


Fig 5. Typical Capacitance Vs. Drain-to-Source Voltage

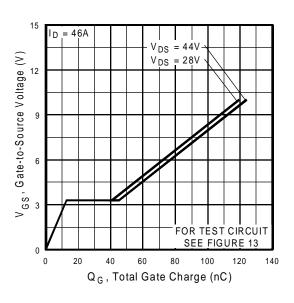


Fig 6. Typical Gate Charge Vs. Gate-to-Source Voltage

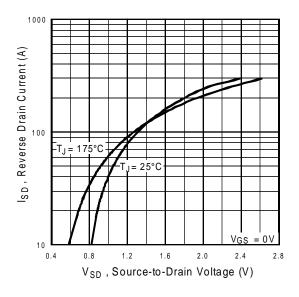


Fig 7. Typical Source-Drain Diode Forward Voltage

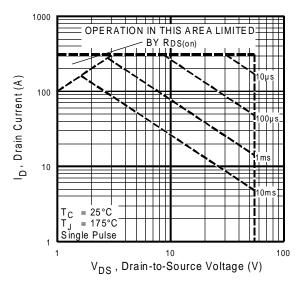


Fig 8. Maximum Safe Operating Area

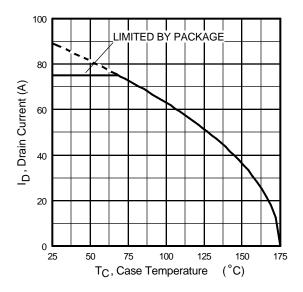


Fig 9. Maximum Drain Current Vs. Case Temperature

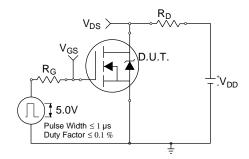


Fig 10a. Switching Time Test Circuit

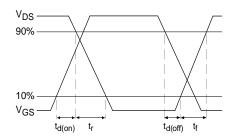


Fig 10b. Switching Time Waveforms

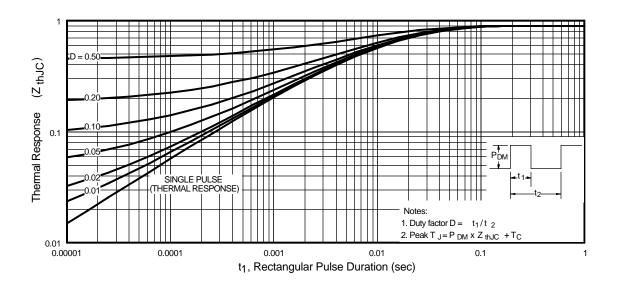


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

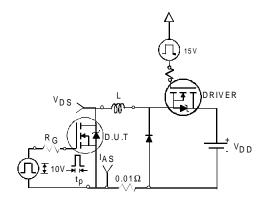


Fig 12a. Unclamped Inductive Test Circuit

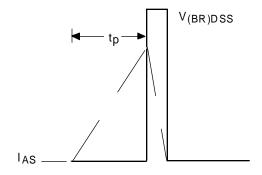


Fig 12b. Unclamped Inductive Waveforms

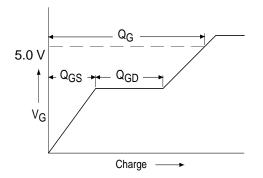


Fig 13a. Basic Gate Charge Waveform

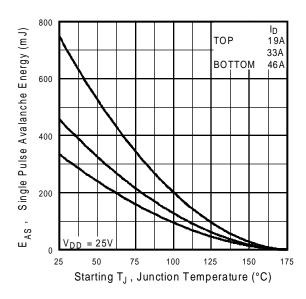


Fig 12c. Maximum Avalanche Energy Vs. Drain Current

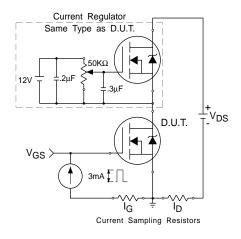
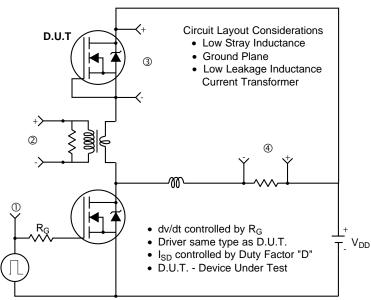
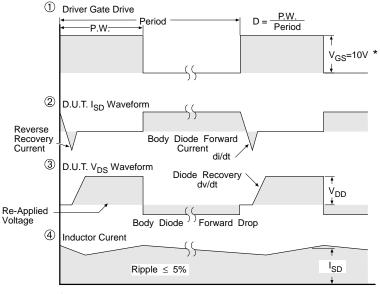


Fig 13b. Gate Charge Test Circuit

Peak Diode Recovery dv/dt Test Circuit





* V_{GS} = 5V for Logic Level Devices

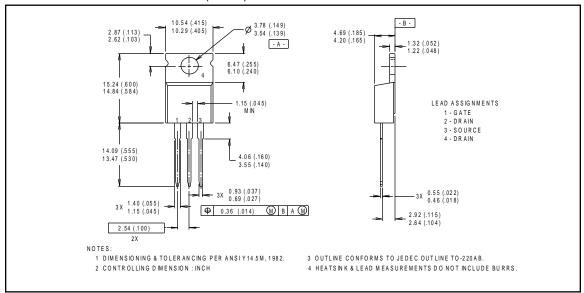
Fig 14. For N-Channel HEXFETS

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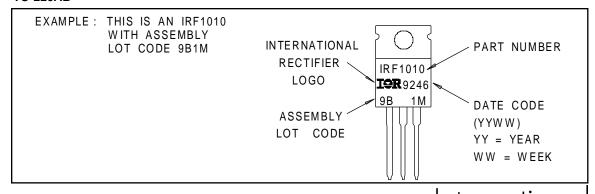
Package Outline

TO-220AB Outline

Dimensions are shown in millimeters (inches)



Part Marking Information TO-220AB



International

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